



Image AF
2823

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of
Tsung et al.

Atty. Docket: TI-30243

Serial No.: 09/921,324

Art Unit: 2823

Filed: August 2, 2001

Examiner: G. Fourson III

Title: Mass Production of Cross-Section TEM Samples by
Focused Ion Beam Deposition and Anisotropic Etching

Amendment-B Under 37 CFR 1.116

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

MAILING CERTIFICATE UNDER 37 C.F.R. §1.8(a)
I hereby certify that the above
correspondence is being deposited with the
U.S. Postal Service with sufficient postage
for First Class mail in an envelope addressed
to: Commissioner for Patents, Alexandria, VA
22313-1450 on the date indicated:

12-12-03

Jackie McBride
Jackie McBride

Dear Sir:

Responsive to Examiner's Office Action dated December
3, 2003, Applicants amend the application as follows: